


<b>Search Notes</b>  	<b>Application/Control No.</b>  10593736	<b>Applicant(s)/Patent Under Reexamination</b>  MIYATAKE ET AL.
	<b>Examiner</b>  DEREK S CHAPEL	<b>Art Unit</b>  2872

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Arnel Lavarias about the restriction	1/16/2009	DSC

INTERFERENCE SEARCH			
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Examiner, Art Unit 2872